


<b>Search Notes</b>  	<b>Application/Control No.</b>  1067954110487358	<b>Applicant(s)/Patent Under Reexamination</b>  CHIN ET AL.EKSTROM, HAKAN
	<b>Examiner</b>  Woods, Eric Woods, Eric	<b>Art Unit</b>  26282628

SEARCHED			
Class	Subclass	Date	Examiner
345	619, 660-665	11/28/2006	EW
715345	859-861, 764-766619-624,642-645,672,676-680	11/28/200611/28/2006	EW EW
715	517	11/28/2006	EW
700	95-98	11/28/2006	EW

SEARCH NOTES		
Search Notes	Date	Examiner
EAST (USPT,USPGPUB,DERWENT,EPO,JPO,IBM-TDB)-see attached search history	11/28/2006	EW

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner